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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/691,020	10/21/2003	Philip Neaves	501317.02 (30302/US)	4992
7590 06/10/2005		EXAMINER		
Kimton N. Eng, Esq. DORSEY & WHITNEY LLP			NGUYEN, TUNG X	
Suite 3400 1420 Fifth Avenue			ART UNIT	PAPER NUMBER
			2829	
Seattle, WA 9	8101		DATE MAILED: 06/10/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)	(N
		10/691,020	NEAVES ET AL.	(h)
	Office Action Summary	Examiner	Art Unit	
		Tung X. Nguyen	2829	
Period fo	The MAILING DATE of this communic or Reply	ation appears on the cover sheet w	rith the correspondence addres	\$S
THE - Exte after - If the - If NC - Failt Any	ORTENED STATUTORY PERIOD FOR MAILING DATE OF THIS COMMUNIC nisions of time may be available under the provisions of SIX (6) MONTHS from the mailing date of this communication of period for reply specified above is less than thirty (30) period for reply is specified above, the maximum stature to reply within the set or extended period for reply with reply received by the Office later than three months after the patent term adjustment. See 37 CFR 1.704(b).	ATION. 37 CFR 1.136(a). In no event, however, may a nication. days, a reply within the statutory minimum of thi tory period will apply and will expire SIX (6) MOI II, by statute, cause the application to become A	reply be timely filed rly (30) days will be considered timely. NTHS from the mailing date of this commu BANDONED (35 U.S.C. § 133).	unication.
Status				
1)⊠	Responsive to communication(s) filed	on 24 May 2005.		
2a)[]	This action is FINAL . 2b	n)⊠ This action is non-final.		
3) 🗌	Since this application is in condition for closed in accordance with the practice	•	· •	erits is
Disposit	ion of Claims			
5)□ 6)⊠ 7)□	Claim(s) 25-32 and 44-47 is/are pendidal of the above claim(s) is/are Claim(s) is/are allowed. Claim(s) 25-32 and 44-47 is/are reject Claim(s) is/are objected to. Claim(s) are subject to restriction	withdrawn from consideration.		
Applicat	ion Papers			
9)[The specification is objected to by the	Examiner.		
10)[The drawing(s) filed on is/are: a	a)□ accepted or b)□ objected to	by the Examiner.	•
	Applicant may not request that any objecti	on to the drawing(s) be held in abeya	nce. See 37 CFR 1.85(a).	
11)	Replacement drawing sheet(s) including the The oath or declaration is objected to be			
Priority (under 35 U.S.C. § 119			
a)		ocuments have been received. ocuments have been received in A the priority documents have beer al Bureau (PCT Rule 17.2(a)).	Application No n received in this National Sta	ge
Attachmen	t(s)			
2) Notice	te of References Cited (PTO-892) te of Draftsperson's Patent Drawing Review (PTO mation Disclosure Statement(s) (PTO-1449 or P ⁻¹ or No(s)/Mail Date 3/04, 4/05, 5/04.	O-948) Paper No	Summary (PTO-413) (s)/Mail Date Informal Patent Application (PTO-152 	2)

DETAILED ACTION

Election/Restrictions

1. Applicant's election without traverse of species IV with claims 25-32, and 44-47 in the reply filed on 5/24/05 is acknowledged.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 25, 27, 29, 30, 32, 44, 46-47 are rejected under 35 U.S.C. 102(b) as being anticipated by Cilingiroglu (u.s.p 5,124,660).

As to claims 25, 30, Cilingiroglu disclose in Figs. 1-5, a method for evaluating an integrated circuit (110 of figure 1) having a plurality of data terminals (112 of figure 1) at which data signals are received, the method comprising: capacitively coupling a test plate (106 of figure 1) to a plurality of signal terminals (112 of figure 1) at which data signals are received; transmitting a data signal from the test plate to one of the plurality of signal terminals (col. 3, lines 31-47); and evaluating the data signal detected by at the signal terminal against a test criteria (col. 3, lines 31-47).

As to claim 27, Cilingiroglu disclose in Figs. 1-5, ceasing reception of the data signal from the first signal terminal (via 516 of figure 5); transmitting a data signal from the test plate to another one of the plurality of signal terminals (via 516 of figure 5); and

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evaluating the data signal detected by other signal terminal against the test criteria (col. 5, lines 30-40).

As to claim 29, Cilingiroglu disclose in Figs. 1-5, decoupling the test plate (106 of figure 1, 502-504 of figure 5) from a voltage reference (via 518) and coupling the test plate (502-504 of figure 5) to a transmitting circuit generating a test signal in response to detecting an input test signal (col. 3, lines 31-47).

As to claim 32, Cilingiroglu discloses in Figs. 1-5, evaluating detected data signal comparing the detected data signal to an expected data signal (col. 3, lines 35-47).

As to claim 44, Cilingiroglu disclose in Figs. 1-5, a test apparatus for an integrated circuit (500 of figure 5, or 110 of figure 1) having plurality of capacitively coupled signal terminals (501 of figure 5) to which a corresponding plurality of receivers are coupled, the receivers generating a respective data signal in response to detecting a respective input data signal (col. 5, lines 30-40), the test apparatus comprising: a test plate (501 of figure 5) to capacitively couple to the signal terminals of the integrated circuit (500 of figure 5); a test transmitter circuit (516, 518 of figure 5) coupled to the test plate (501 of figure 5) to transmit a data signal to at least one of the signal terminals through the test plate (col. 5, lines 30-40); and a test unit (522 of figure 5) coupled to the test signal terminals to evaluate the detected data signal against test criteria (col. 5, lines 30-40).

As to claim 46, Cilingiroglu disclose in Figs. 1-5, the test unit (522 of figure 5) comprising test circuitry to determine the functionality of the receivers coupled to the

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signal terminals and the integrity of a capacitor through which the signal terminal is capacitively coupled (col. 5, lines 30-40).

As to claim 47, Cilingiroglu disclose in Figs. 1-5, the test unit comprises test circuitry to compare the detected data signal against an expected data signal (col. 5, lines 30-40);

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claim 26 is rejected under 35 U.S.C. 103(a) as being unpatentable over Cilingiroglu (u.s.p 5,124,660), in view of Vest et al. (u.s.p 6,242,941).

As to claim 26, Cilingiroglu discloses in Figs. 1-5, all of the limitations except for placing the remaining data terminals of the plurality in a high-impedance state.

However, Vest et al. disclose in col. 1, lines 63-67, the terminals of the plurality in a high-impedance state for reducing noise in the testing mode. Therefore, It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify the system of Cilingiroglu, and provides the terminals of plurality in high-impedance state, as taught by Vest et al., for reducing noise in the testing mode (col. 1, lines 63, 67).

6. Claims 28, 31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Cilingiroglu (u.s.p 5,124,660), in view of Parker et al. (u.s.p 6,087,842).

As to claim 28, Cilingirolu discloses in Figs. 1-5, all of the limitations except for forming the test plate from a conductive plate layer formed on the semiconductor die. However, Parker et al. disclose in Figs. 6A, forming the test plate (614 of figure 6A) from a conductive plate layer formed on the semiconductor die (600 of figure 6A) for effectively testing the electrical continuity between the paths of integrated circuit (see the abstract). Therefore, It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify the system of Cilingiroglu, and provide the test plate from a conductive plate layer formed on the semiconductor die, as taught by Parker et al, for effectively testing the electrical continuity between the paths of integrated circuit (see the abstract).

As to claim 31, Cilingirolu discloses in Figs. 1-5, the integrated circuit comprising a memory device (110 of figure 1).

7. Claim 45 is rejected under 35 U.S.C. 103(a) as being unpatentable over Cilingiroglu (u.s.p 5,124,660), in view of Seki (u.s.p 6,714,031).

As to claim 45, Cilingiroglu discloses in Figs. 1-5, all of the limitations except for the test transmitter comprising a buffer circuit. However, Seki disclose in Figs. 6, the test transmitter comprising a buffer circuit (61 of figure 6) for delaying in each stage (col. 6, lines 40-45). Therefore, It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify a system of Cilingiroglu, and provide the buffer circuit, as taught by Seki for delaying in each stage (col. 6, lines 40-45).

Conclusion

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8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tung X. Nguyen whose telephone number is (571) 272-1967. The examiner can normally be reached on 8:30am-5:00pm M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nestor Ramirez can be reached on (571) 272-2034. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TN 6/7/05

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